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Microbeam analysis - Guidelines for orientation measurement using electron backscatter diffraction (ISO 24173:2024)

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Normative references	1
3	Terms and definitions	1
4	Equipment for EBSD	6
5	Operating conditions	7
5.1	Specimen preparation	7
5.2	Specimen alignment	7
5.3	Common steps in collecting an EBSP	7
5.3.1	Setting the microscope operating conditions	7
5.3.2	Detector and working distances	8
5.3.3	Camera integration/exposure time	8
5.3.4	Binning	8
5.3.5	EBSP averaging	9
5.3.6	EBSP background correction/EBSP signal correction	9
5.3.7	Band detection	10
6	Calibrations required for indexing of EBSPs	11
7	Analytical procedure	14
7.1	Operating conditions	14
7.2	Equipment stability check	15
7.3	EBSD analysis	15
8	Measurement uncertainty	15
8.1	General	15
8.2	Uncertainty of crystal orientation measurement	15
8.3	Absolute orientation	15
8.4	Relative orientation	15
9	Reporting the results	16
Annex A (informative)	Principle of EBSD	17
Annex B (informative)	Specimen preparation for EBSD	18
Annex C (informative)	Brief introduction to crystallography and EBSP indexing, and other information useful for EBSD	24
Bibliography		39